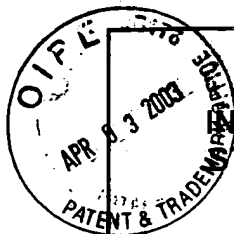
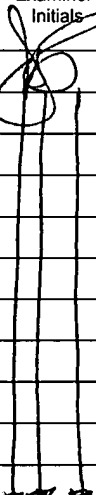


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Substitute for form 1449A/PTO				Application Number	10/061,459
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Filing Date	1/31/02
				First Named Inventor	Steven Teig, et al.
				Group Art Unit	2171
				Examiner Name	
Sheet	1	of	2	Attorney Docket Number	SPLX.P0091

RELATED U.S. PATENT APPLICATIONS						
Examiner* Initials	Cite No. ¹	U.S. Patent Application		Name of Patentee or Applicant of Cited Document	Date of Filing MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Serial Number				
	1.	10/062,017		Steven Teig & Asmus Hetzel	01-31-02	
	2.	10/062,014		Steven Teig & Asmuz Hetzel	01-31-02	
	3.	10/062,044		Steven Teig & Asmus Hetzel	01-31-02	
	4.	10/066,264		Steven Teig & Asmuz Hetzel	01-31-02	
	5.	10/066,188		Steven Teig & Asmus Hetzel	01-31-02	
	6.	10/062,992		Steven Teig & Asmus Hetzel	01-31-02	
	7.	10/061,474		Steven Teig & Asmuz Hetzel	01-31-02	
	8.	10/061,719		Steven Teig & Asmus Hetzel	01-31-02	
	9.	10/066,456		Steven Teig & Asmus Hetzel	01-31-02	
	10.	10/062,993		Steven Teig & Asmus Hetzel	01-31-02	
	11.	10/062,047		Steven Teig & Asmuz Hetzel	01-31-02	

U.S. PATENT DOCUMENTS						
Examiner* Initials	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code* (if known)			
	12.	5,649,165		Jain et al.	07-15-97	
	13.	6,301,687	B1	Jain et al.	10-09-01	

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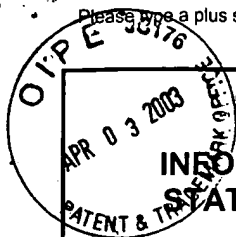
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				Group Art Unit	2171
				Examiner Name	
Sheet	2	of	2	Attorney Docket Number	SPLX.P0091

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner* Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁶
	14.	D. Jongeneel, R. Otten, Y. Watanabe and R. K. Brayton, Area and Search Space Control for Technology Mapping, 37 th Design Automation Conference, 86-91, 2000.	
	15.	Henrik Reif Andersen, An Introduction to Binary Decision Diagrams, October 1997 (minor revisions April 1998), 36 pp.	
	16.	Jerry Burch and David Long, Efficient Boolean Function Matching, Proc. ICCAD 1992, 408-411.	
	17.	John Fishburn, A Depth-Decreasing Heuristic for Combinational Logic; or How to Convert Ripple-Carry Adder into a Carry-Lookahead Adder or Anything In-Between, Proceedings of the 27 th Design Automation Conference, 361-364, 1990.	
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	19.	Kurt Keutzer, DAGON: Technology Binding and Local Optimization by DAG Matching, Proceedings of the 24 th Design Automation Conference, 341-347, 1987	
	20.	Randal Bryant, Symbolic Boolean Manipulation with Ordered Binary Decision Diagrams, CMU CS Tech Report CMU-CS-92-160.	
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	22.	Yuji Kukimoto, Robert K. Brayton, and Prashant Sawkar, Delay-Optimal Technology Mapping by DAG Covering, Dept. of Electrical Engineering and Computer Science, University of California, Berkeley, Strategic CAD Laboratories, Intel Corp., October 1997.	
	23.	Zbigniew J. Czech, et al., An Optimal Algorithm for Generating Minimal Perfect Hashing Functions, Information Processing Letters, 43(5); 257-264, October 1992	

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